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This listing of claims will replace all prior versions, and listings, of claims in

the application

Listing of Claims:

1. (Previously Presented) A method for forming a pattern in a film

carried on a substrate, said method comprising:

obtaining a mold of a material, which mold is hard relative to the film,

the film comprising a polymeric composition including an internal mold

release agent and capable of being deformed by said mold at a temperature of

less than 200°C.:

the mold having first and second protruding features spaced apart from

each other and a recess formed thereby, the first and second features and the

recess having a shape forming a mold pattern and providing at least one mold

pattern lateral dimension which is less than 200 nm;

urging the mold into the film under a molding pressure;

the thickness of the film under the protruding features of the mold being

reduced to form areas of reduced thickness, thereby forming the mold pattern in

the film;

photocuring, thermally curing, or both thermally curing and photocuring the

polymeric composition;

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removing the mold from the film; and

removing from the film the areas of reduced thickness, thereby forming

exposed portions of the surface of the substrate which underlie the areas of

reduced thickness such that the exposed portions of the surface of the substrate

substantially replicate the mold pattern and have at least one lateral dimension

which is less than 200 nm;

methacrylate),

wherein the polymeric composition comprises a thermosettable polymeric

composition and a photocurable polymeric composition.

2 (Previously Presented) The method of claim 1, wherein the

polymeric composition comprises a block copolymer, a grafted polymer, a

telechelic polymer, a star polymer, a dendrimer, or any combination thereof.

3. (Previously Presented) The method of claim 1, wherein the

polymeric composition comprises: poly(methyl methacrylate), poly(bisphenol-A

carbonate), poly(methylhexadecylsiloxane), poly(methylacrylate), poly(n-butyl

acrylate), poly(octadecyl methacrylate), poly(isobutyl methacrylate), poly(butyl

methacrylate), poly(vinylacetate), poly(vinyl stearate), poly(ethylene oxide),

lyniy)ylog stearate)/poly(methyl polycaprolactone. poly(α-methylstyrene).

poly(methylhexadecylsiloxane)/poly(methyl

methacrylate).

poly(octadecyl methacrylate)/poly(methyl methacrylate), poly(butyl methacrylate-

co-isobutylmethacrylate), poly(butyl methacrylate-co-methyl methacrylate),

poly(dimethylsiloxane-co-α-methylstyrene), poly(ethylene-co-vinylacate)-graft(t-

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maleic anhydride), poly(vinyl chloride-co-vinylacetate), poly(vinyl chloride-coisobutylvinylether), poly(chlorotrifluorethylene-co-vinylidene fluoride), or any

combination thereof.

4. (Original) The method of claim 1, wherein the polymeric

composition comprises an oligomer, said oligomer comprising an epoxy resin, an

acrylic (methylacrylic) oligomer, a reactive polysiloxane oligomer, or any

combination thereof.

5. (Original) The method of claim 1, wherein the polymeric

composition further comprises a monomer, said monomer comprising a $C_8\text{-}C_{20}$

alkyl methacrylate, a fluorinated alkyl (meth)acrylate monomer, or any

combination thereof.

6. (Previously Presented) The method of claim 1, wherein the

polymeric composition further comprises a crosslinker, said crosslinker

comprising divinyl benzene, trimethylolpropane triacrylate, or any combination

thereof.

(Canceled).

8. (Previously Presented) The method of claim 1, wherein said

polymeric composition is capable of being deformed at a temperature of less

than about 100°C.

9. (Canceled).

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10. (Previously Presented) The method of claim 1, wherein said photocurable polymeric composition is capable of curing in less than about 2 seconds on exposure to radiation.

11. (Previously Presented) The method of claim 1, wherein said photocurable polymeric composition has a viscosity of greater than about 2 poise at 25°C.

12. (Original) The method of claim 11, wherein said photocurable polymeric composition has a viscosity in the range of about 10 poise to about 30 poise.

13. (Previously Presented) The method of claim 1, wherein said photocurable polymeric composition comprises an oligomer, said oligomer comprising silicon atoms.

14. (Previously Presented) The method of claim 1, wherein said photocurable polymeric composition is capable of crosslinking in less than about 2 seconds on exposure to radiation.

15. (Previously Presented) The method of claim 1, wherein said photocurable polymeric composition comprises up to about 90 weight percent monomer.

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16. (Currently Amended) The method of claim 1, wherein said nanoimprint resist film further comprises a plasticizer, a monomer, a crosslinker, an additive, or any combination thereof.

17. (Currently Amended) The method of claim 1, wherein said naneimprint-resist film comprises from about 20 weight percent to 100 weight percent of a plasticizer, and up to about 30 weight percent of a mold release agent.

(Canceled).

(Previously Presented) The method of claim 1, wherein sub-50 nanometer structures are formed.

20 - 29. (Canceled).

30. (Previously Presented) A method for forming a plurality of structures having at least one dimension less than 200 nm, said method comprising:

obtaining a mold of a material, which mold is hard relative to a nanoimprint resist,

the nanoimprint resist comprising a polymeric composition including an internal mold release agent and capable of being deformed by said mold at a temperature of less than 200°C., wherein the polymeric composition comprises a

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thermosettable polymeric composition and a photocurable polymeric

composition;

the mold having first and second protruding features spaced apart from

each other and a recess formed thereby, the first and second features and the

recess having a shape forming a mold pattern and providing at least one mold

pattern lateral dimension which is less than 200 nm;

urging the mold into the nanoimprint resist under a molding pressure;

the thickness of the nanoimprint resist under the protruding features of the

mold being reduced to form areas of reduced thickness, thereby forming the

mold pattern in the nanoimprint resist, the mold pattern comprising a plurality of

structures having at least one dimension less than 200 nm;

photocuring, thermally curing, or both thermally curing and photocuring the

polymeric composition;

removing the mold from the nanoimprint resist, the polymeric composition

retaining said plurality of structures; and

removing from the nanoimprint resist the areas of reduced thickness,

thereby forming exposed portions of the surface of the substrate which underlie

the areas of reduced thickness such that the exposed portions of the surface of

the substrate substantially replicate the mold pattern and have at least one lateral

dimension which is less than 200 nm.

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31 - 34. (Cancelled).

35. (Previously Presented) The method of claim 30 wherein the curing

comprises ultraviolet exposure.

36. (Currently Amended) The method of claim 30_wherein the curing

comprises thermal treatment.

37. (Previously Presented) The method of claim 30 wherein the curing

comprises both ultraviolet exposure and thermal treatment.

38. (Previously Presented) A method for forming a pattern in a film

carried on a substrate, said method comprising:

obtaining a mold of a material, which mold is hard relative to the film,

the film comprising a polymeric composition including an internal mold

release agent and a crosslinker and capable of being deformed by said mold at a

temperature of less than 200°C.;

the mold having first and second protruding features spaced apart from

each other and a recess formed thereby, the first and second features and the

recess having a shape forming a mold pattern and providing at least one mold

pattern lateral dimension which is less than 200 nm;

urging the mold into the film under a molding pressure;

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the thickness of the film under the protruding features of the mold being reduced to form areas of reduced thickness, thereby forming the mold pattern in the film:

crosslinking the polymeric composition;

removing the mold from the film; and

removing from the film the areas of reduced thickness, thereby forming exposed portions of the surface of the substrate which underlie the areas of reduced thickness such that the exposed portions of the surface of the substrate substantially replicate the mold pattern and have at least one lateral dimension which is less than 200 nm.

(Previously Presented) The method of claim 38, wherein the 39. polymeric composition comprises: poly(methyl methacrylate), poly(bisphenol-A carbonate), poly(methylhexadecylsiloxane), poly(methylacrylate), poly(n-butyl acrylate), poly(octadecyl methacrylate), poly(isobutyl methacrylate), poly(butyl methacrylate), poly(vinylacetate), poly(vinyl stearate), poly(ethylene oxide), poly(a-methylstyrene). poly(vinyl stearate)/poly(methyl polycaprolactone, poly(methylhexadecylsiloxane)/poly(methyl methacrylate), methacrylate). poly(octadecyl methacrylate)/poly(methyl methacrylate), poly(butyl methacrylateco-isobutylmethacrylate), poly(butyl methacrylate-co-methyl methacrylate), poly(dimethylsiloxane-co-α-methylstyrene), poly(ethylene-co-vinylacate)-graft(tmaleic anhydride), poly(vinyl chloride-co-vinylacetate), poly(vinyl chloride-co-

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isobutylvinylether), poly(chlorotrifluorethylene-co-vinyldiene fluoride), or any combination thereof.

- 40. (Previously Presented) The method of claim 38, wherein the polymeric composition comprises an oligomer, said oligomer comprising an epoxy resin, an acrylic (methylacrylic) oligomer, a reactive polysiloxane oligomer, or any combination thereof.
- 41. (Previously Presented) The method of claim 38, wherein the polymeric composition further comprises a monomer, said monomer comprising a C₈-C₂₀ alkyl methacrylate, a fluorinated alkyl (meth)acrylate monomer, or any combination thereof.
- 42. (Previously Presented) The method of claim 38, wherein crosslinker is divinyl benzene, trimethylolpropane triacrylate, or any combination thereof.
- (Previously Presented) The method of claim 1, in which the polymeric composition comprises a single or multiple layers of composites.
- (Previously Presented) The method of claim 1, in which the mold imprints at least one layer of multiple layers of a composite.
- 45. (Previously Presented) The method of claim 1 comprising both thermally curing and photocuring the polymeric composition after imprinting by the mold.

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46. (Previously Presented) The method of claim 30, in which the polymeric composition comprises a single or multiple layers of composites.

47. (Previously Presented) The method of claim 30, in which the mold

imprints at least one layer of multiple layers of a composite.

48. (Canceled).

49. (Currently Amended) A method for forming a pattern in a film

carried on a substrate, said method comprising:

obtaining a mold of a material, which mold is hard relative to the film,

the film comprising from about 20 to 100 wt% of a thermoplastic polymer

and an internal mold release agent, and capable of being deformed by said mold

at a temperature of less than 200°C.;

the mold having first and second protruding features spaced apart from

each other and a recess formed thereby, the first and second features and the

recess having a shape forming a mold pattern and providing at least one mold

pattern lateral dimension which is less than 200 nm;

urging the mold into the film under a molding pressure;

the thickness of the film under the protruding features of the mold being

reduced to form areas of reduced thickness, thereby forming the mold pattern in

the film;

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removing the mold from the film; and

removing from the film the areas of reduced thickness, thereby forming

exposed portions of the surface of the substrate which underlie the areas of

reduced thickness such that the exposed portions of the surface of the substrate

substantially replicate the mold pattern and have at least one lateral dimension

which is less than 200 nm.

50. (Previously Presented) The method of claim 49, wherein the

thermoplastic polymer comprises poly(butyl methacrylate).

51. (Previously Presented) The method of claim 49, wherein the

thermoplastic polymer comprises poly(methylhexadecylsiloxane).

52. (Previously Presented) The method of claim 49, wherein the

thermoplastic polymer comprises polystyrene.

53. (Previously Presented) The method of claim 49, wherein the

thermoplastic polymer comprises poly(octyl methacrylate).

54. (Previously Presented) The method of claim 49, wherein the

thermoplastic polymer comprises poly(vinylchloride-co-vinylacetate).

55. (Previously Presented) The method of claim 49, wherein the

thermoplastic polymer comprises poly(vinylacetate).